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Question Paper Code: 56403

B.E. / B.Tech. DEGREE EXAMINATION, NOV 2019

Sixth Semester

Electronics and Communication Engineering

15UEC603- VLSI DESIGN

(Regulation 2015)

Duration: Three hours

Maximum: 100 Marks

Answer ALL Questions

PART A - (5 x 1 = 5 Marks)

- In continuous assignment left hand side must be CO1-R
(a) Net (b) Reg (c) Scalar or vector net (d) Scalar or vector reg
- CMOS technology is used in developing CO2-U
(a) Microprocessors (b) Microcontrollers
(c) Digital logic circuits (d) all of the mentioned
- In CMOS circuits, which type of power dissipation occurs due to switching of transient current and charging & discharging of load capacitance? CO3-U
(a) Static dissipation (b) Dynamic dissipation
(c) Both a and b (d) None of the above
- Charge leakage and noise margin problems can be addressed by adding _____ CO4-U
(a) Keeper circuit (b) domino gate (c) pass transistor (d) transmission gate
- The number of test vectors for exhaustive testing is calculated by CO5-A
(a) $2^{(m+n)}$ (b) $2^{((m+n)/2)}$ (c) $2^{(m-n)}$ (d) $2^{2(m+n)}$

PART – B (5 x 3= 15Marks)

- What are gate primitives? CO1-U
- Define the lambda layout rules. CO2-R
- Define logical effort and parasitic delay. CO3-R

9.	What is meant by synchronizers.		CO4-R
10.	What is meant by a test program?		CO5-U
PART – C (5 x 16= 80Marks)			
11.	(a) (i) Write a Verilog program for 2 to 4 decoder in dataflow modeling and behavioral modeling.	CO1-U	(8)
	(ii) Write the Verilog code for full adder in structural level modeling with diagram.	CO1-U	(8)
Or			
	(b) (i) Explain in detail blocking and non-blocking assignment.	CO1-U	(8)
	(ii) Explain how to represent the gate delays in Verilog HDL.	CO1-U	(8)
12.	(a) Explain in detail DC transfer characteristic of CMOS inverter	CO2-U	(16)
Or			
	(b) Explain the different steps involved in SOI CMOS fabrication process with neat diagrams	CO2-U	(16)
13.	(a) Analyze the static and dynamic power dissipation in CMOS circuits with necessary diagrams and expressions.	CO3-Ana	(16)
Or			
	(b) (i) Discuss the different reliability problems related to the design of reliable CMOS chip	CO3-Ana	(10)
	(ii) Discuss the principle of constant field scaling and examine its effect on device characteristics.	CO3-Ana	(6)
14.	(a) Discuss the comparison of circuit families	CO4 -U	(16)
Or			
	(b) (i) Discuss the domino logic with neat diagram.	CO4- U	(8)
	(ii) Explain the problem of metastability with neat diagrams and expressions.	CO4-U	(8)
15.	(a) Describe the scan based approaches and built in self-test to design for testability in detail.	CO5- U	(16)
Or			
	(b) (i) Discuss the Silicon debug principles in detail	CO5-U	(8)
	(ii) Explain the Boundary scans techniques.	CO5-U	(8)

